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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Complete if Known		
			Application Number	10/758710-Conf. #6546	
			Filing Date	January 16, 2004	
			First Named Inventor	Martin W. Rupich	
			Art Unit	1762	
			Examiner Name	Not Yet Assigned	
Sheet	1	of	3	Attorney Docket Number	0002802.00174US1






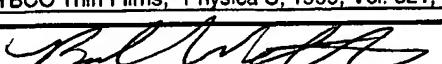
U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	AA*	US-2002/0056401-A1	05-16-2002	Rupich et al.	
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	AD*	US-5,231,074	07-27-1993	Cima et al.	
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	AF*	US-5,683,967	11-04-1997	Frenkel	
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	AT*	US-6,569,811	05-27-2003	Shi	
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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)			
	BA	WO-00/058530	10-05-2000	American Superconductor Corporation	
	BB	WO-00/58044	10-05-2000	American Superconductor Corporation	
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	BD	WO-01/08170	02-01-2001	American Superconductor Corporation	
Examiner Signature				Date Considered	1/11/08

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BE	WO-01/08231	02-01-2001	American Superconductor Corporation		
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BG	WO-01/08233	02-01-2001	American Superconductor Corporation		
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BQ	WO-99/17307	04-08-1999	American Superconductor Corporation		

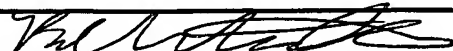
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
    	CA	Ashworth, et al., "AC Losses in Silver Clad Tc Superconducting Tapes," Chinese Journal of Physics, 1996, Vol. 34(2-11), pp. 232-242.	
	CB	Babu, et al., "New Chemically Stable, Nano-Size Artificial Flux Pinning Centres in (RE)-Ba-Cu-O Superconductors," Superconductor Sci. and Tech., 2003, Vol. 16, L44-L45.	
	CC	Beach, et al., "Sol-Gel Synthesis of Rare Earth Aluminate Films as Buffer Layers for High Tc Superconducting Films," Mat. Res. Soc. Symp. Proc., 1998, Vol. 495, pp. 263-270.	
	CD	Carr, et al., "Filamentary YBCO Conductors for AC Applications," I.E.E.E. Transactions on Applied Superconductivity, 1999, Vol. 9(2), pp. 1475-1478.	
	CE	Chevchenko et al., "Proposal to Convert a Second-Generation High Temperature Superconducting DC tape into an AC Tape," 6 pp.	
	CF	di Uccio et al., "Phase Competition Between Y2BaCuO5 and Y2O3 Precipitates in Y-rich YBCO Thin Films," Physica C, 1999, Vol. 321, pp. 162-176.	
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CG	Gammel et al., "Observation of Hexagonally Correlated Flux Quanta in YBa ₂ Cu ₃ O ₇ , Phys. Rev. Lett., 1987, Vol. 59(22), pp. 2592-2595.	
CH	Glowacki, et al., "A New Method for Decreasing Transport AC Losses in Multifilamentary Coated Superconductors," Physica C, 2001, Vol. 357-360, pp. 1213-1217.	
CI	Haugan et al., "Island Growth of Y ₂ BaCuO ₅ Nanoparticles in (211-1.5nm/123 ~10nm) x N Composite Multilayer Structures to Enhance Flux Pinning of YBa ₂ Cu ₃ O _{7-δ} Films," J. Mater. Res., 2003, Vol. 18(11), pp. 2618-2623.	
CJ	Huang, "Oxide Barriers and Their Effect on AC Losses of Bi,Pb (2223) Multifilamentary Tapes," 1998, Applied Superconductivity Conference.	
CK	Jin et al., "Superconducting Properties of YBa ₂ Cu ₃ O _{7-δ} with Partial Rare Earth Substitution," Physica C, 1991, Vol. 173, pp. 75-79.	
CL	Kehl, "The Principles of Metallographic Laboratory Practice," Third Edition, 1949, McGraw-Hill Book Company.	
CM	Lee et al., "Alternative Buffer Architectures for High Critical Current Density YBCO Superconducting Deposits on Rolling Assisted Biaxially-Textured Substrates," Jpn. J. Appl. Phys., 1999, Vol. 38, pp. L178-L180.	
CN	MacManus-Driscoll et al., "Strongly Enhanced Current Densities in Superconducting Coated Conductors of BaZrO ₃ -Doped YBa ₂ Cu ₃ O _{7-x} ," Superconductivity Tech. Center, Los Alamos Nat'l Lab., pp. 1-7.	
CO	Majoros, et al., "Modelling of the Influence of Magnetic Screening on Minimisation of Transport AC Losses in Multifilamentary Superconductors," I.E.E. Transactions on Applied Superconductivity, 2001, Vol. 1(1), pp. 2780-2783.	
CP	Malozevoff, "Second Generation HTS Wire: An Assessment," 2004, American Superconductor Brochure.	
CQ	Morrell et al., "Sol-Gel Synthesis of Epitaxial Films of (Sr, Ba) Bi ₂ (Nb,Ta) ₂ O ₉ and Bi ₄ Ti ₃ O ₁₂ on [100] SrTiO ₃ , Mat. Res. Soc. Symp. Proc., 1998, Vol. 495, pp. 271-276.	
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CS	Oomen, et al., "AC Loss in High-Temperature Superconducting Conductors, Cables, and Windings for Power Devices," Superconductor Science and Technology, 2004, Vol. 17, pp. S394-S399.	
CT	Paranthaman et al., "Growth of Biaxially Textured RE ₂ O ₃ Buffer Layers on Rolled-Ni Substrates Using Reactive Evaporation for HTS-Coated Conductors," Superconductor Sci. Tech., 1999, Vol. 12, pp. 319-325.	
CU	Rupich et al., "Growth and Characterization of Oxide Buffer Layers for YBCO Coated Conductors," I.E.E. Trans. on Appl. Supercon., 1999, Vol. 9(2), pp. 1527-1530.	
CV	Shoup et al., "Epitaxial Thin Film Growth of Lanthanum and Neodymium Aluminate Films on Roll-Textured Nickel Using a Sol-Gel Method," J. Am. Cer. Soc., 1998, Vol. 81, pp. 3019-3021.	
CW	Skakle "Crystal Chemical Substitutions and Doping of YBa ₂ Cu ₃ O _x and Related Superconductors," Materials Science and Engineering, 1998, Vol. R23, pp. 1-40.	
CX	Wolf, et al., "Silicon Processing for the VLSI Era," 1986, Vol. 1, pp. 539-574, Lattice Press, Sunset Park, CA.	
CY	Wu, et al., "Twin Boundaries and Critical Current Densities of YBa ₂ Cu ₃ O ₇ Thick Films Fabricated by the BaF ₂ Process," Superconductor Sci. and Tech., 2003, Vol. 16, pp. 1127-1133.	

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